

Search Notes**Application/Control No.**

10/765,276

Examiner

Vuthe Siek

Applicant(s)/Patent under Reexamination

TAKEOKA ET AL.

Art Unit

2825

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 716 | 4-6 | 2/22/2006 | VS |
| 702 | 58,59 | 5/8/2006 | VS |
| 702 | 117-119 | 5/8/2006 | VS |
| 702 | 185,189 | 5/8/2006 | VS |
| 324 | 238,500 | 5/8/2006 | VS |
| 324 | 512,527 | 5/8/2006 | VS |
| 714 | 700,744 | 5/8/2006 | VS |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---|-----------|------|
| EAST ALL DATABASES & IEEE (SEE SEARCH HISTORY PRINTOUTS) | 2/22/2006 | VS |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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